

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		09/898,043	HAYASHI	
Examiner		Art Unit	2826	Page 1 of 1
Johannes P Mondt				

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-6,096,394	05-2000	Hashimoto et al.	257/466
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages
	U	Peng, T., and Piprek, J., "Refractive Index of AlGaN Alloys", Electronics Letters, 21 <sup>st</sup> November 1996, Volume 32, Issue 24.
	V	Steigerwald, D., et al, "III-V Nitride Semiconductors for High-Performance Blue and Green Light-Emitting Devices", JOM, Volume 49, Issue 9, pp. 18-23 (1997).
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.